

Notice of References CitedApplication/Control No.
10/727,301Applicant(s)/Patent Under
Reexamination
LEAN ET AL.Examiner
ALEX NOGUEROLAArt Unit
1753

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,156,970	01-2007	Lean et al.	204/547
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frénée et al. (« A Multilayer Microelectrode array for Particle separation by Dielectrophoresis, » Micro Total Analysis systems 2002, Volume 1, 578-580, Y. Baba et al. (eds.))
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Alex Noguera
4/14/07